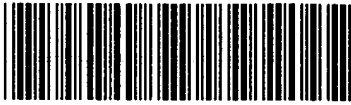


Search Notes

Application/Control No.

10/671,772

Examiner

EDMUND H. LEE

Applicant(s)/Patent under
Reexamination

MORIYAMA ET AL.

Art Unit

1732

SEARCHED

Class	Subclass	Date	Examiner
UPDATED		12/4/2006	EHL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
264	248,250	12/4/2006	EHL
	254,255		
	279.1		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
UPDATED	12/4/2006	EHL